

#### **Features**

#### • Split Gate Trench MOSFET technology

- Excellent package for heat dissipation
- High density cell design for low RDS(ON)

#### **Product Summary**

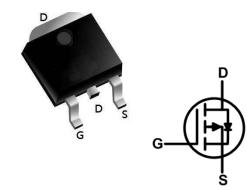


BVDSS	RDSON	ID
-100V	45mΩ	-30A

#### **Applications**

- Battery switching application
- Hard switched and high frequency circuits
- Power management

#### **TO252-3L Pin Configuration**



**Absolute Maximum Ratings:** 

Symbol	Parameter		Value	Units
V <sub>DSS</sub>	Drain-to-Source Voltage	-100	V	
T	Continuous Drain Current $T_C = 25$ °CContinuous Drain Current $T_C = 100$ °C		-30	A
$I_D$			-17.8	A
$I_{DM}^{a1}$	Pulsed Drain Current	-112	A	
$E_{AS}^{a2}$	Single pulse avalanche energy	225	mJ	
$I_{AR}$	Single pulse avalanche current	30	A	
$V_{GS}$	Gate-to-Source Voltage		±20	V
$P_{D}$	Power Dissipation	83	W	
т. т	Operating Junction and Storage Temperature Range		150 55 to 150	°C
T <sub>J</sub> , T <sub>stg</sub>			150, -55 to 150	
$T_{ m L}$	Maximum Temperature for Solder	ring	260	$^{\circ}\mathrm{C}$

#### **Thermal Characteristics:**

Symbol	Parameter	Value	Units
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case	1.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	102	°C/W



## Electrical Characteristics (TA= 25°C unless otherwise specified):

Static Ch	Static Characteristics							
Cyren le o l	Donomoton	T. (C. 1'4'	Value			T.L 14		
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units		
$V_{\rm DSS}$	Drain to Source Breakdown Voltage	$V_{GS}=0V, I_{D}=-250\mu A$	-100			V		
I <sub>DSS</sub>	Drain to Source Leakage Current	$V_{DS}$ =-100V, $V_{GS}$ =0V			1	μΑ		
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	$V_{GS}$ =-20V, $V_{DS}$ =0V			100	nA		
$I_{GSS(R)}$	Gate to Source Reverse Leakage	$V_{GS} = +20V, V_{DS} = 0V$			-100	nA		
$V_{GS(TH)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{D}=-250 \mu A$	-1.5	-2.0	-2.5	V		
R <sub>DS(ON)1</sub>	Drain-to-Source On- Resistance	$V_{GS}$ =-10V, $I_{D}$ =-20A		45	55	mΩ		
R <sub>DS(ON)2</sub>	Drain-to-Source On- Resistance	$V_{GS}$ =-4.5V, $I_{D}$ =-10A		55	65	mΩ		

Dynamic	Characteristics					
Cyren le o l	Domorroston	Test Conditions	Value			TT '4
Symbol	Parameter		Min.	Typ.	Max.	Units
C <sub>iss</sub>	Input Capacitance	$V_{GS} = 0V$		2100		
Coss	Output Capacitance	$V_{DS} = -50V$		168		pF
$C_{rss}$	Reverse Transfer Capacitance	f = 1.0MHz		26		
$R_{g}$	Gate resistance	$V_{GS} = 0V, V_{DS} Open$		2.8		Ω

Resistive	Switching Characteristics					
Cr	D	Test Conditions		TT '4		
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$t_{d(ON)}$	Turn-on Delay Time	$I_{D} = -20A$		8.2	1	
tr	Rise Time	$I_D = -20A$ $V_{DS} = -50V$		19.6	1	<b>42</b> G
$t_{d(OFF)}$	Turn-Off Delay Time	$V_{GS} = -10V$		62.8		ns
$t_{\mathrm{f}}$	Fall Time	$R_G = 5\Omega$		41.4		
$Q_{g}$	Total Gate Charge	$V_{GS} = -10V$		38		
$Q_{gs}$	Gate Source Charge	$V_{DS} = -50V$		6.4		nC
$Q_{gd}$	Gate Drain Charge	$I_D = -20A$		6.8		

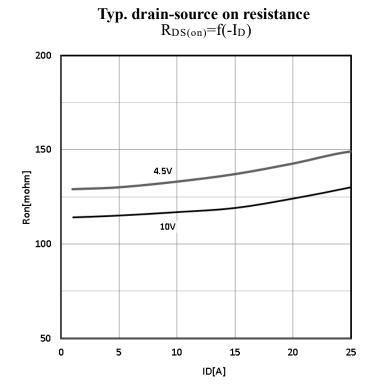
Source-Drain Diode Characteristics								
Symbol	Danamatan	Test Conditions	Value			Units		
Syllibol	Parameter	Test Conditions	Min.	Typ.	Max.	Ullits		
$V_{SD}$	Diode Forward Voltage	$I_{S}$ =-20A, $V_{GS}$ =0V			-1.2	V		
t <sub>rr</sub>	Reverse Recovery time	$I_{S}$ =-20A, $V_{DD}$ =-50V		68		ns		
Qrr	Reverse Recovery Charge	$dI/dt=100A/\mu s$	-	200		nC		

 $<sup>^{</sup>a1}$ : Repetitive rating; pulse width limited by maximum junction temperature  $^{a2}$ : L=0.5mH,  $R_g{=}25\Omega,$  Starting  $T_J{=}25~^{\circ}C$ 

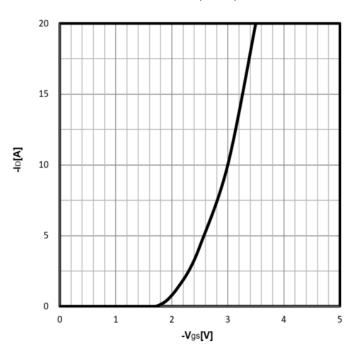


#### **Characteristics Curve:**

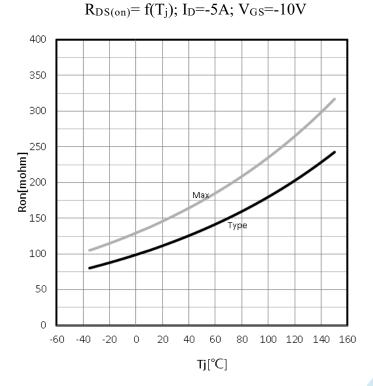
Typ. output characteristics  $-I_D = f(-V_{DS})$ 



Typ. transfer characteristics  ${}^{-}I_D {=} f({}^{-}V_{\rm GS})$ 



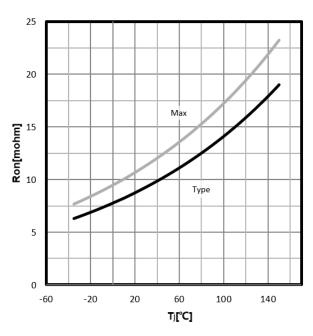
Drain-source on-state resistance



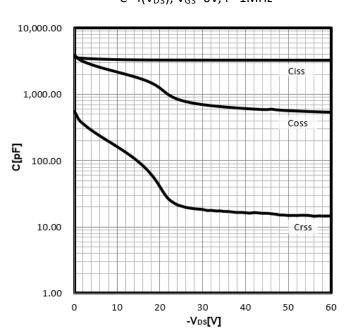


Drain-source on-state resistance

 $R_{DS(on)}$ =f(T<sub>j</sub>);  $I_D$ =-20A;  $V_{GS}$ =-10V

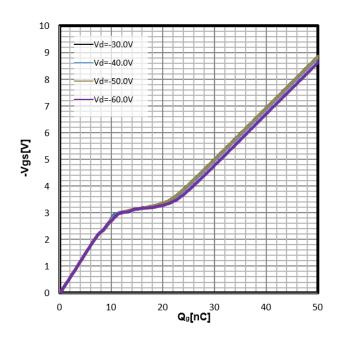


**Typ.** capacitances C = f(V<sub>DS</sub>); V<sub>GS</sub>=0V; f = 1MHz



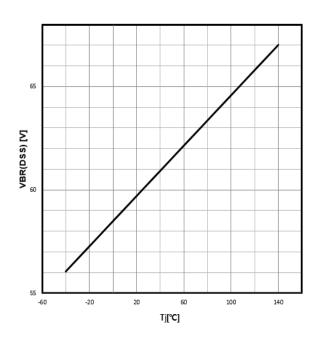
Typ. gate charge

 $V_{GS}$ = $f(Q_{gate})$ ;  $I_D$ =-20A

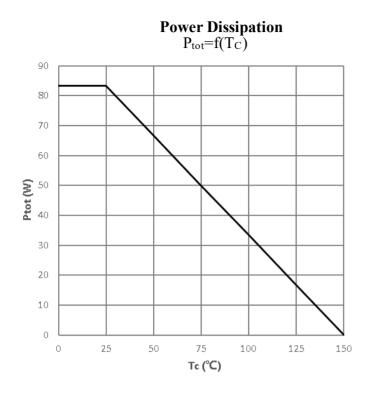


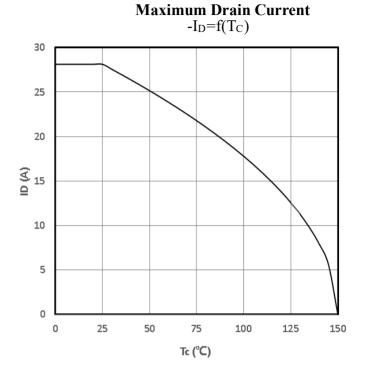
Drain-source breakdown voltage

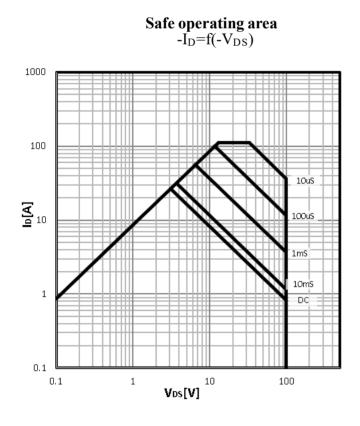
 $V_{BR(DSS)}=f(T_j); I_D=-250uA$ 

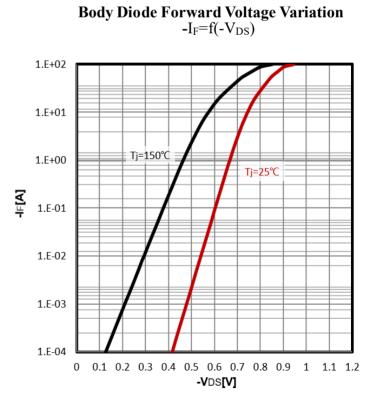




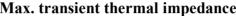


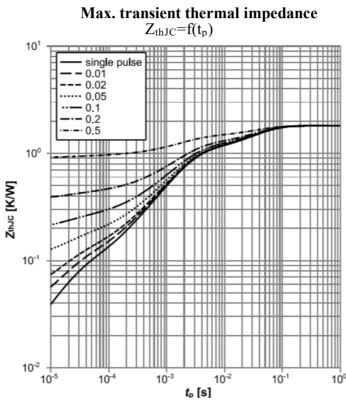








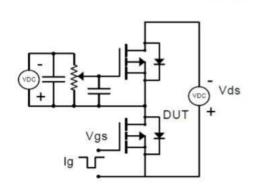


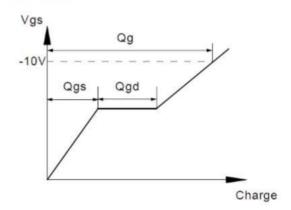




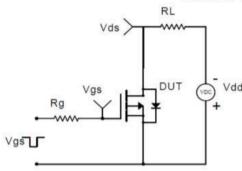
### **Test Circuit and Waveform:**

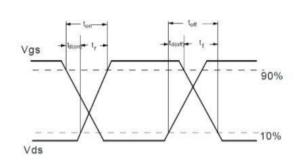
#### Gate Charge Test Circuit & Waveform



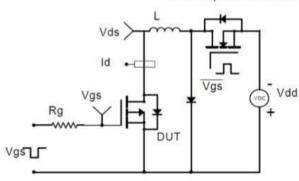


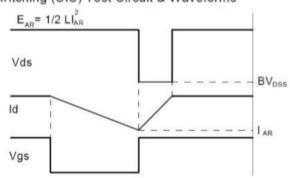
Resistive Switching Test Circuit & Waveforms



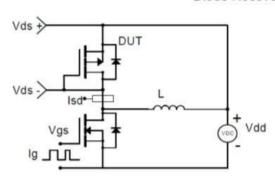


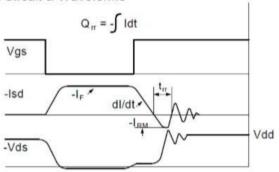
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





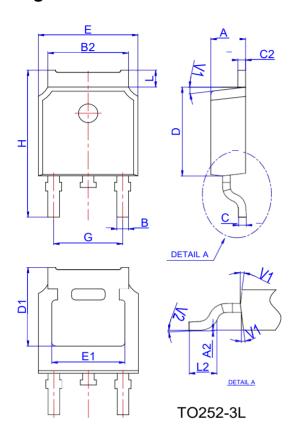
#### Diode Recovery Test Circuit & Waveforms





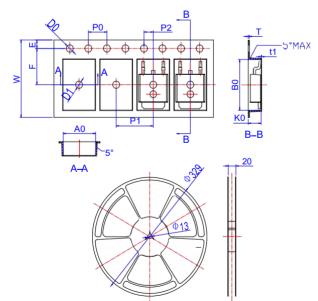


# Package Mechanical Data TO252-3L



	Dimensions						
Ref.		Millimeter	s		Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.	
Α	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1	5.30REF			(	).209REF		
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
Н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

## Reel Spectification-TO252-3L



	Dimensions					
Ref.		Millimeters		Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583